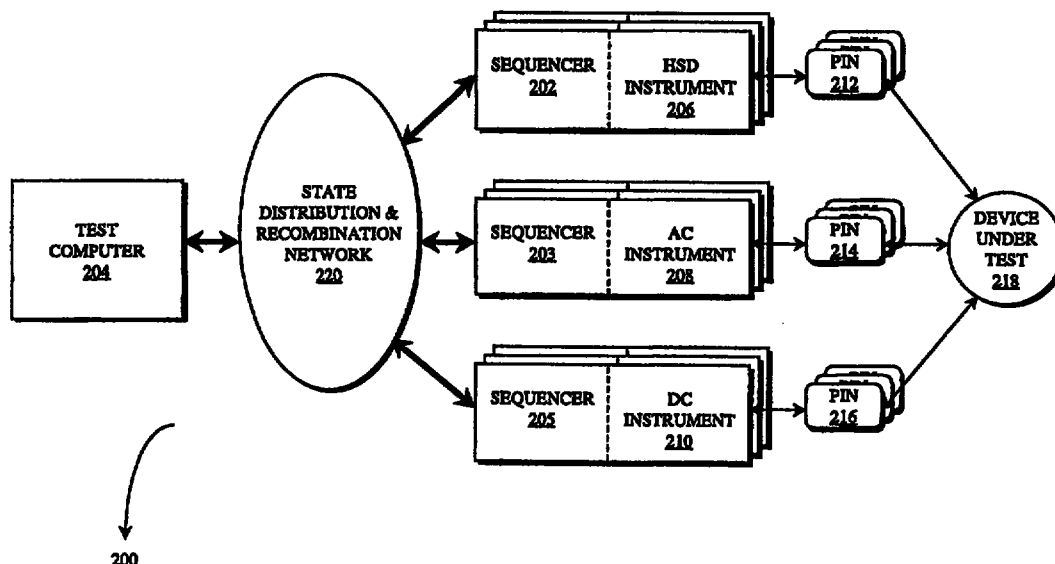




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(54) Title: HIGH SPEED, REAL-TIME, STATE INTERCONNECT FOR AUTOMATIC TEST EQUIPMENT



(57) Abstract

A tester is disclosed in which state coherency is maintained between functional blocks of the tester by way of a novel state distribution and recombination network. The network includes a plurality of nodes configured to provide point-to-point links can be adjusted by selecting a suitable node configuration and by programming delay circuitry included in each node. The network therefore maintains state coherence between the functional blocks by ensuring that delays throughout the test system are both deterministic and adjustable. The tester is particularly useful for testing complex, mixed-signal semiconductor devices.